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FIG. 1

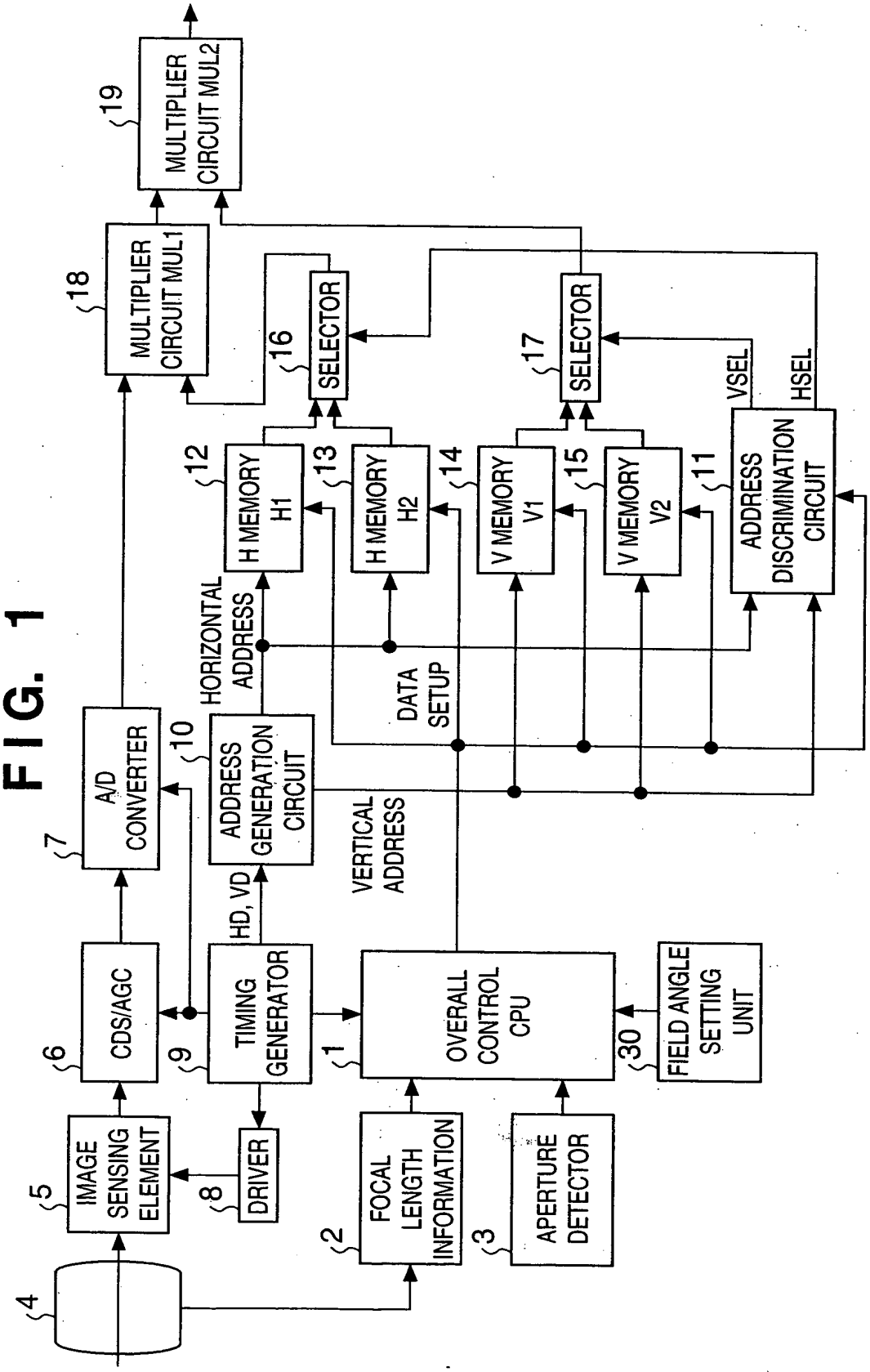

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FIG. 2B

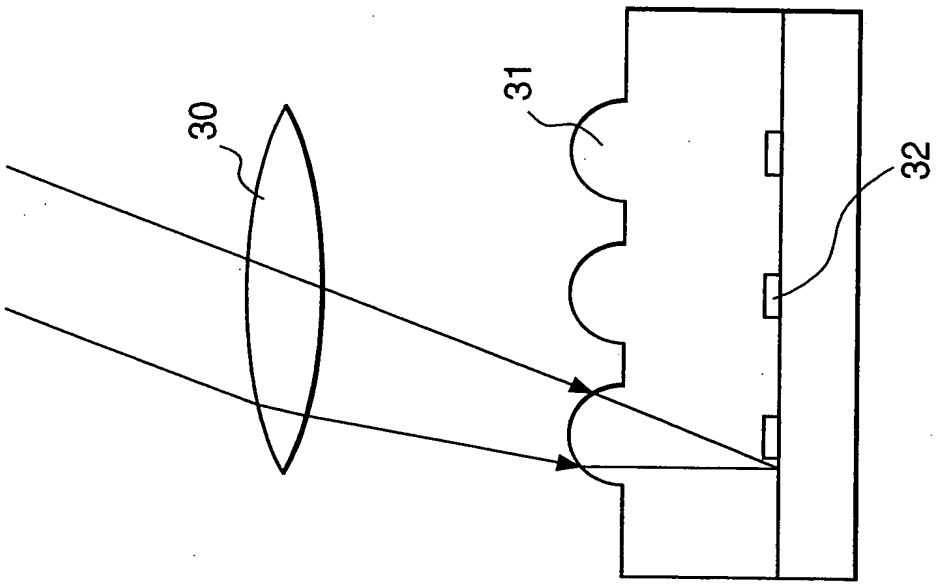

FIG. 2A

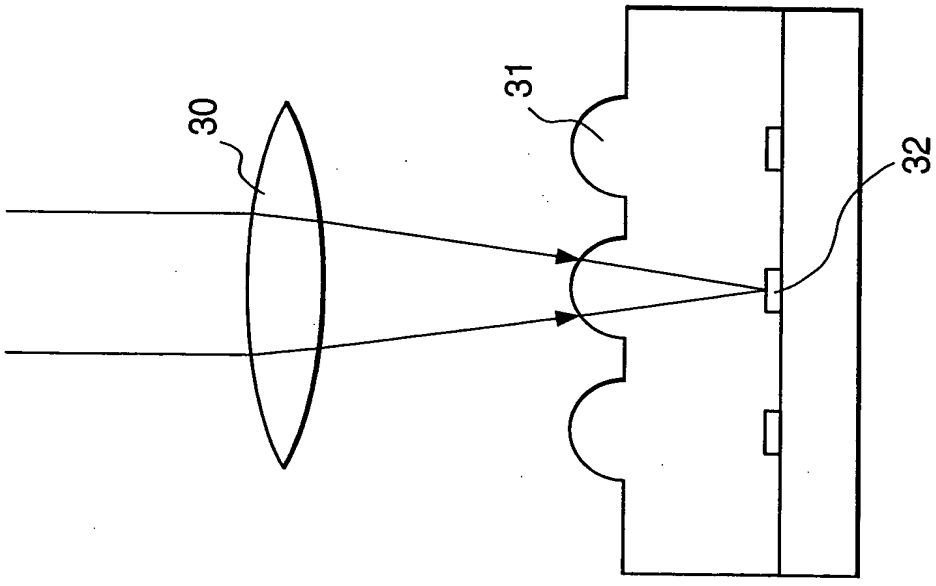

FIG. 3B

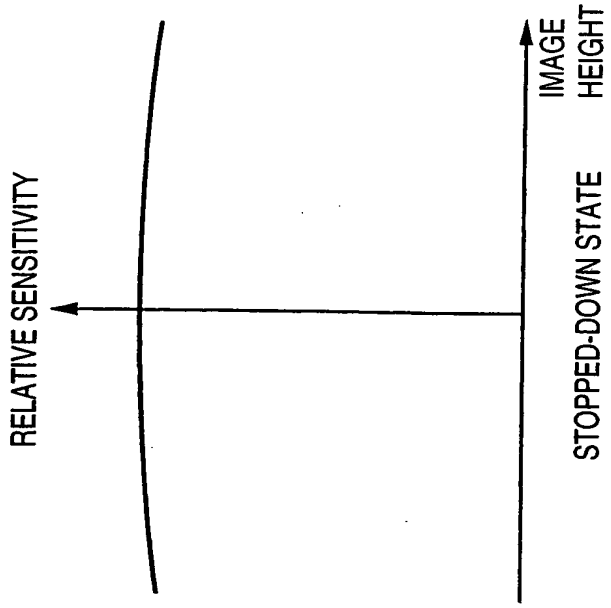
RELATIVE SENSITIVITY
IMAGE HEIGHT
STOPPED-DOWN STATE

FIG. 3A

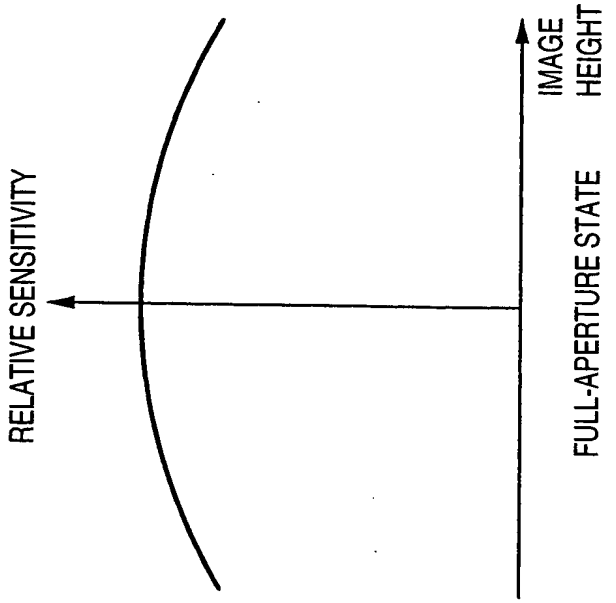
RELATIVE SENSITIVITY
IMAGE HEIGHT
FULL-APERTURE STATE

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FIG. 4

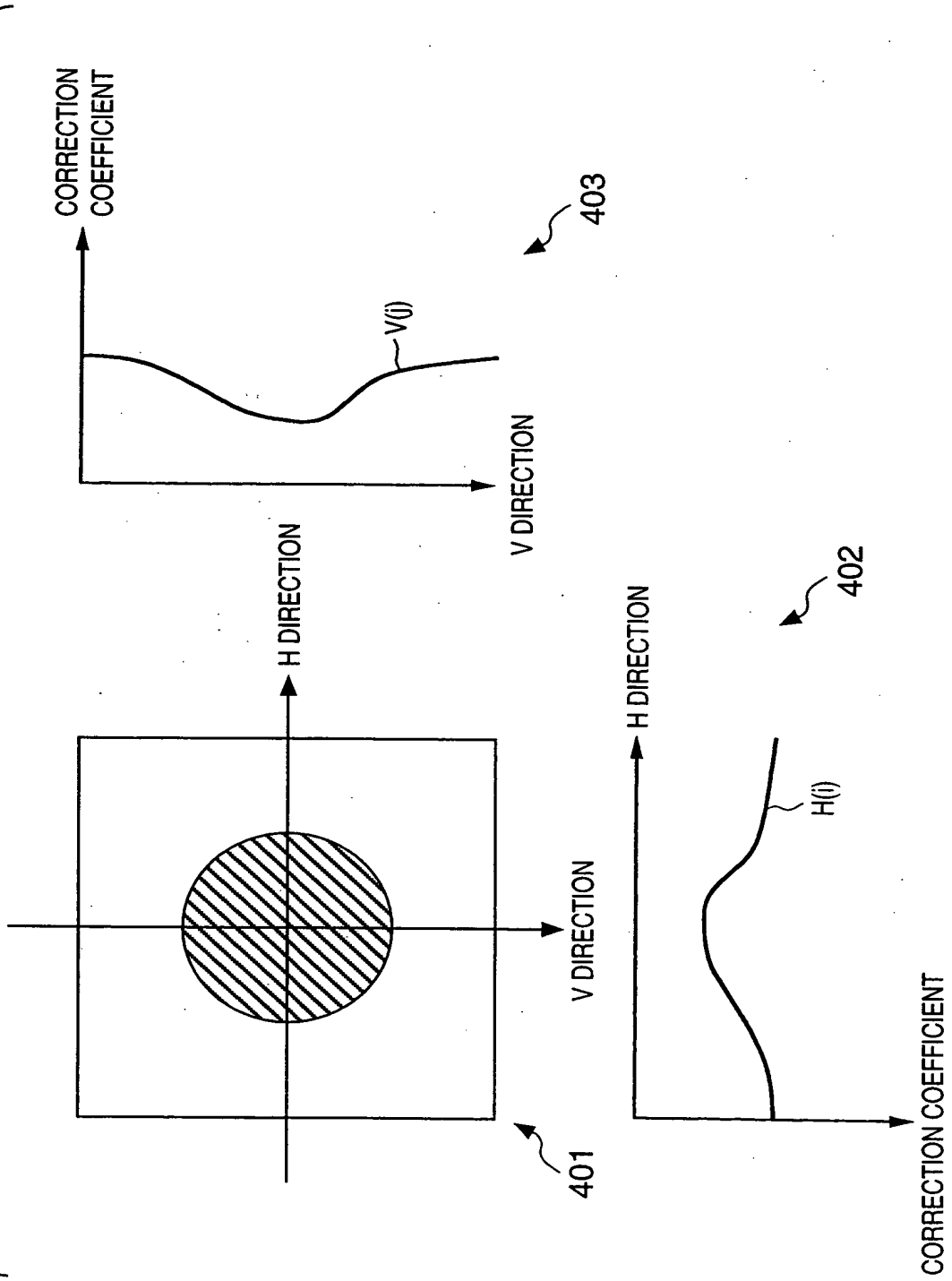

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FIG. 5

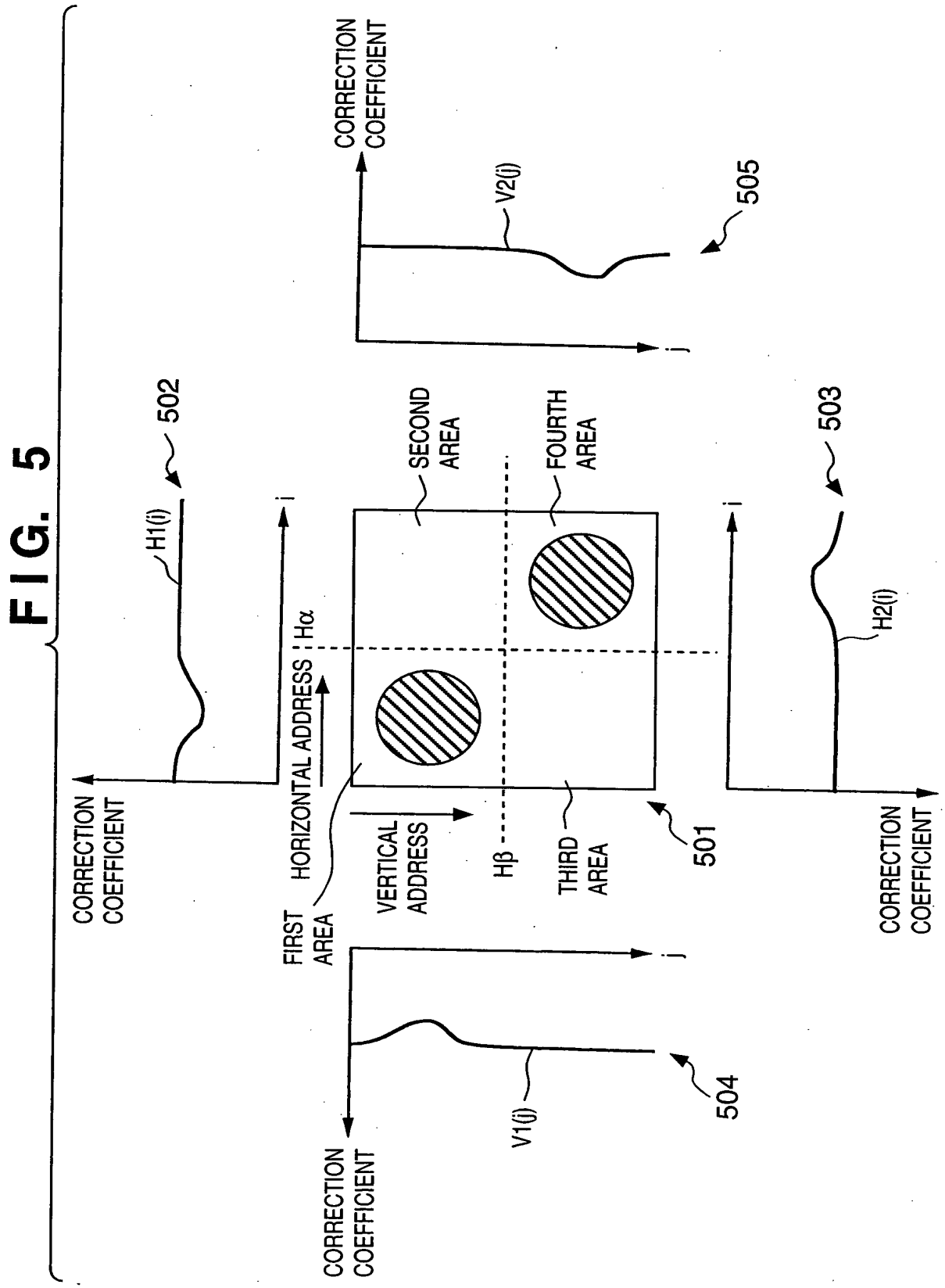

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FIG. 6

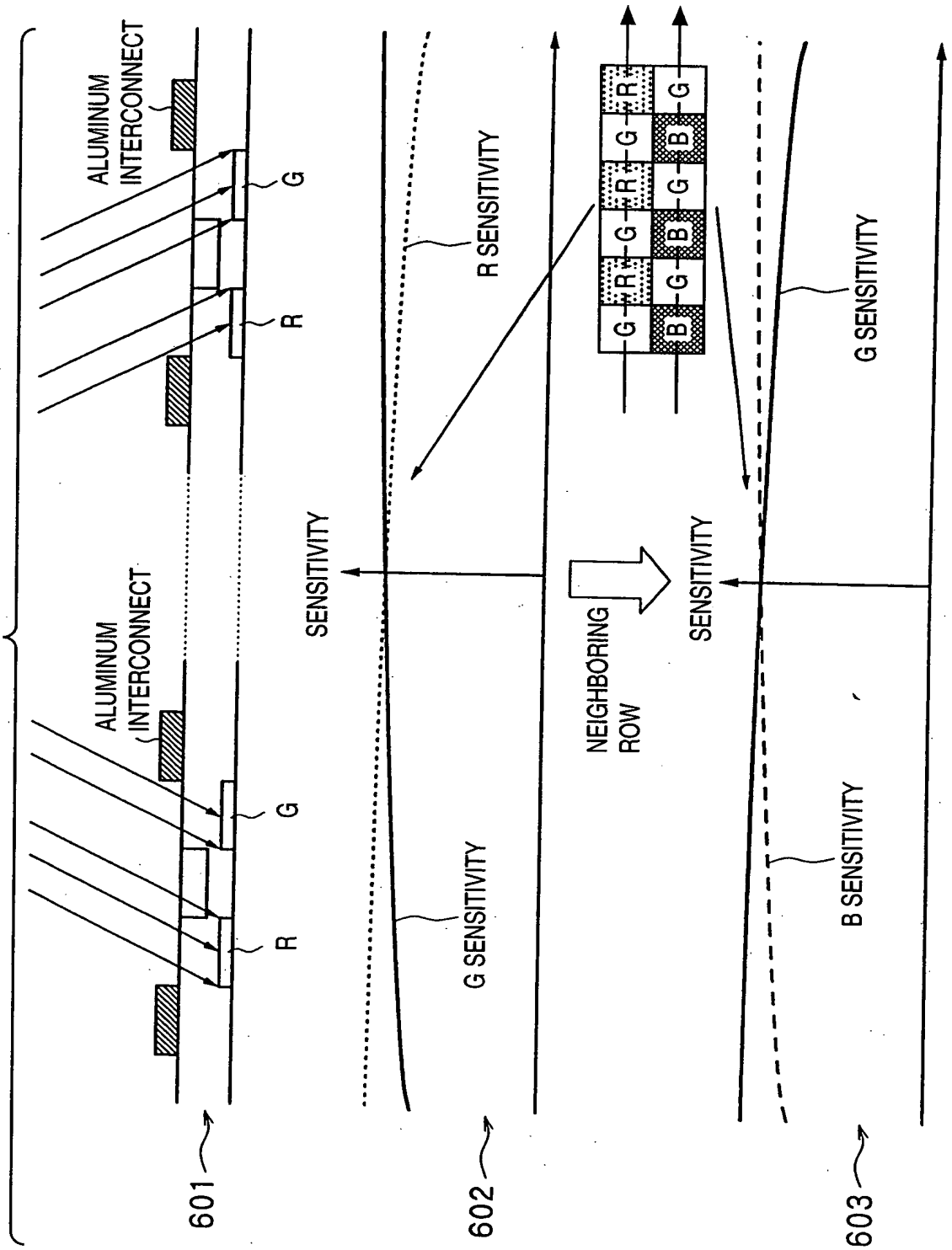

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FIG. 7

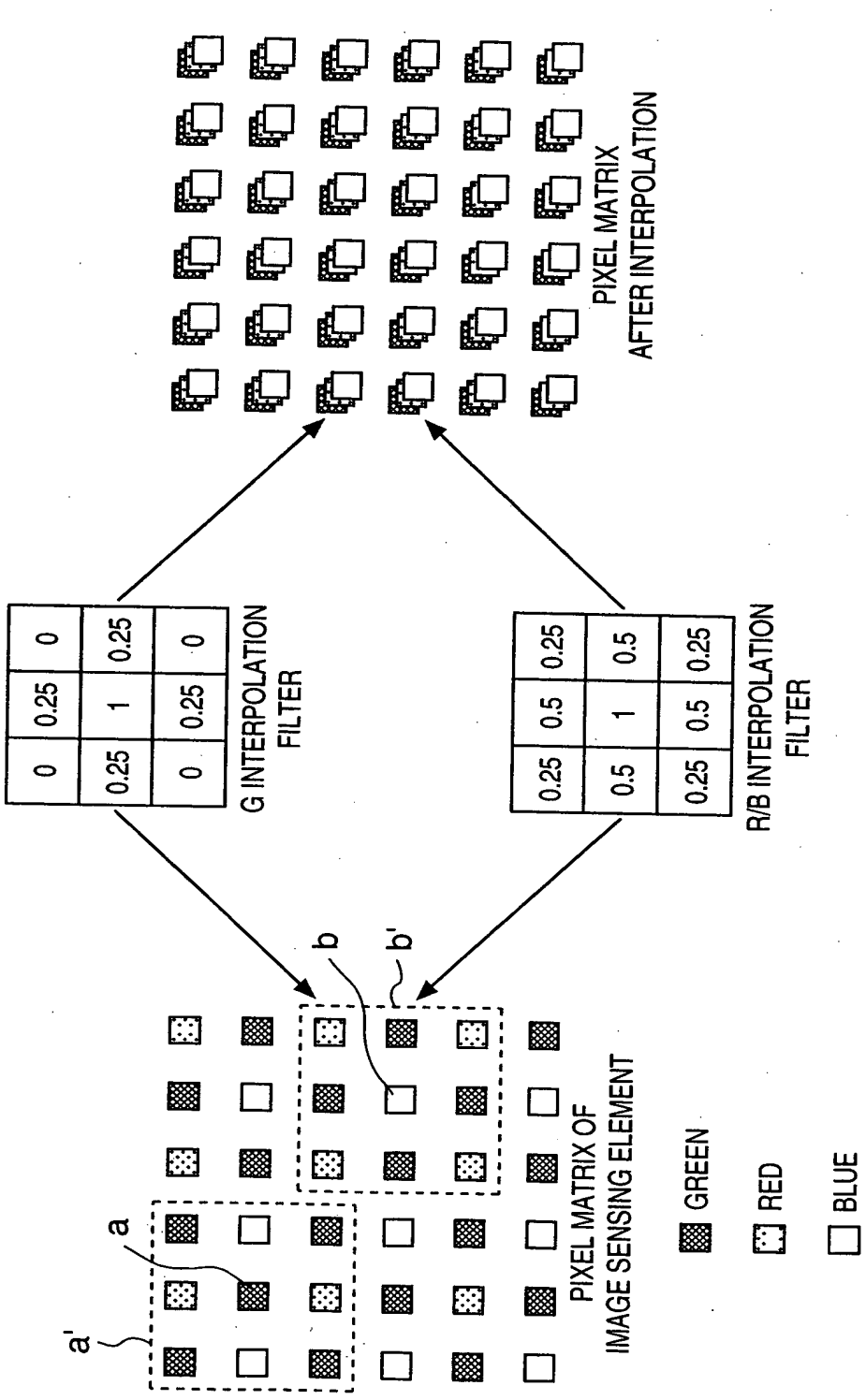

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FIG. 8

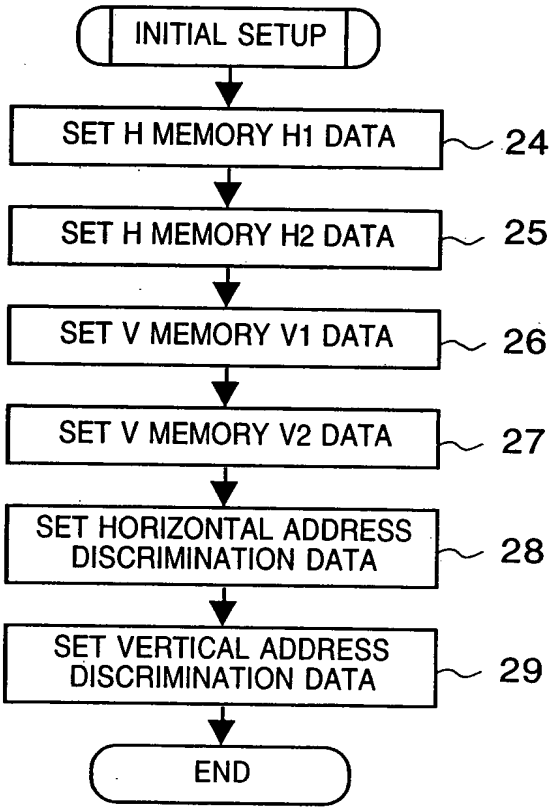

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FIG. 9

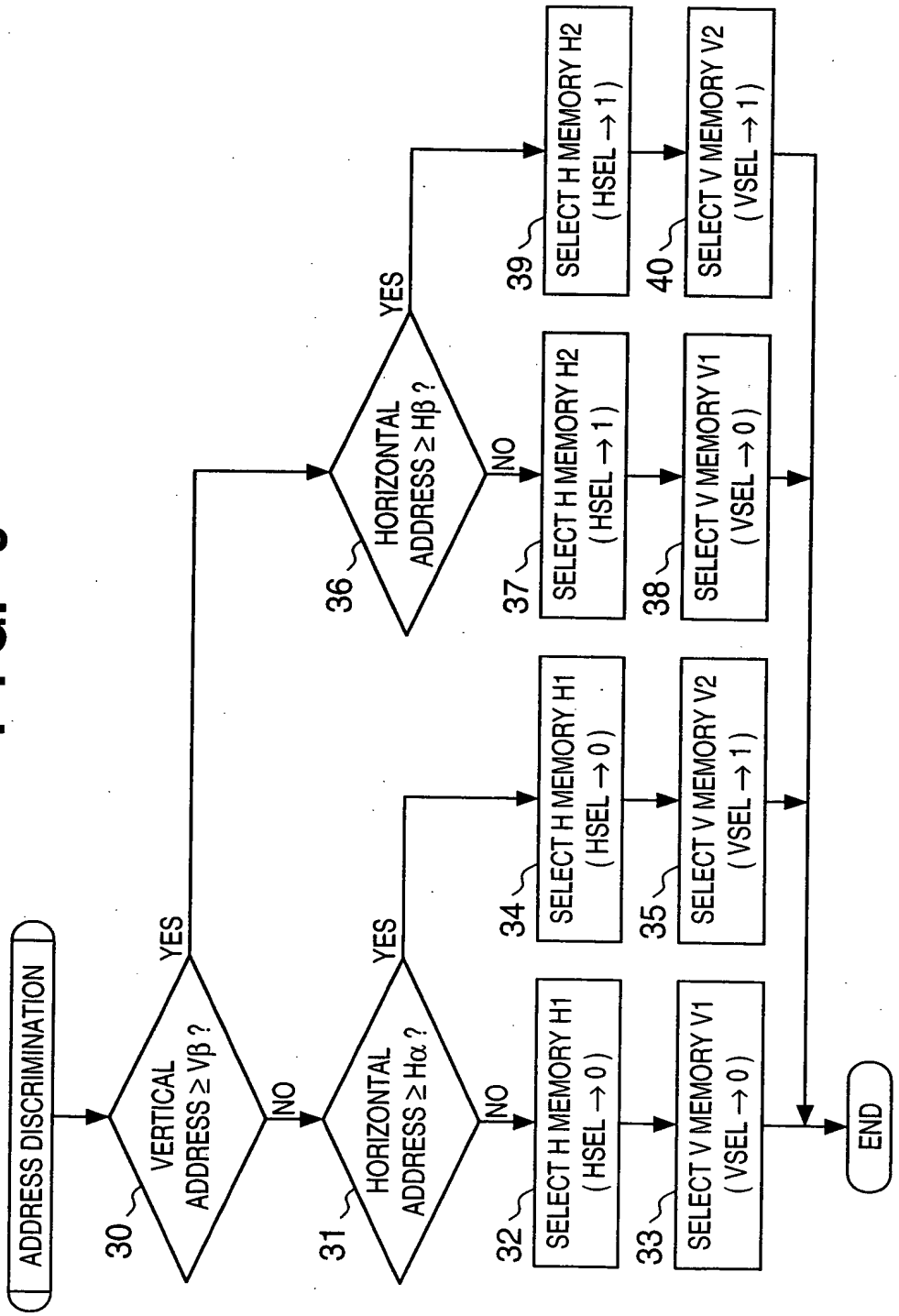

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FIG. 10

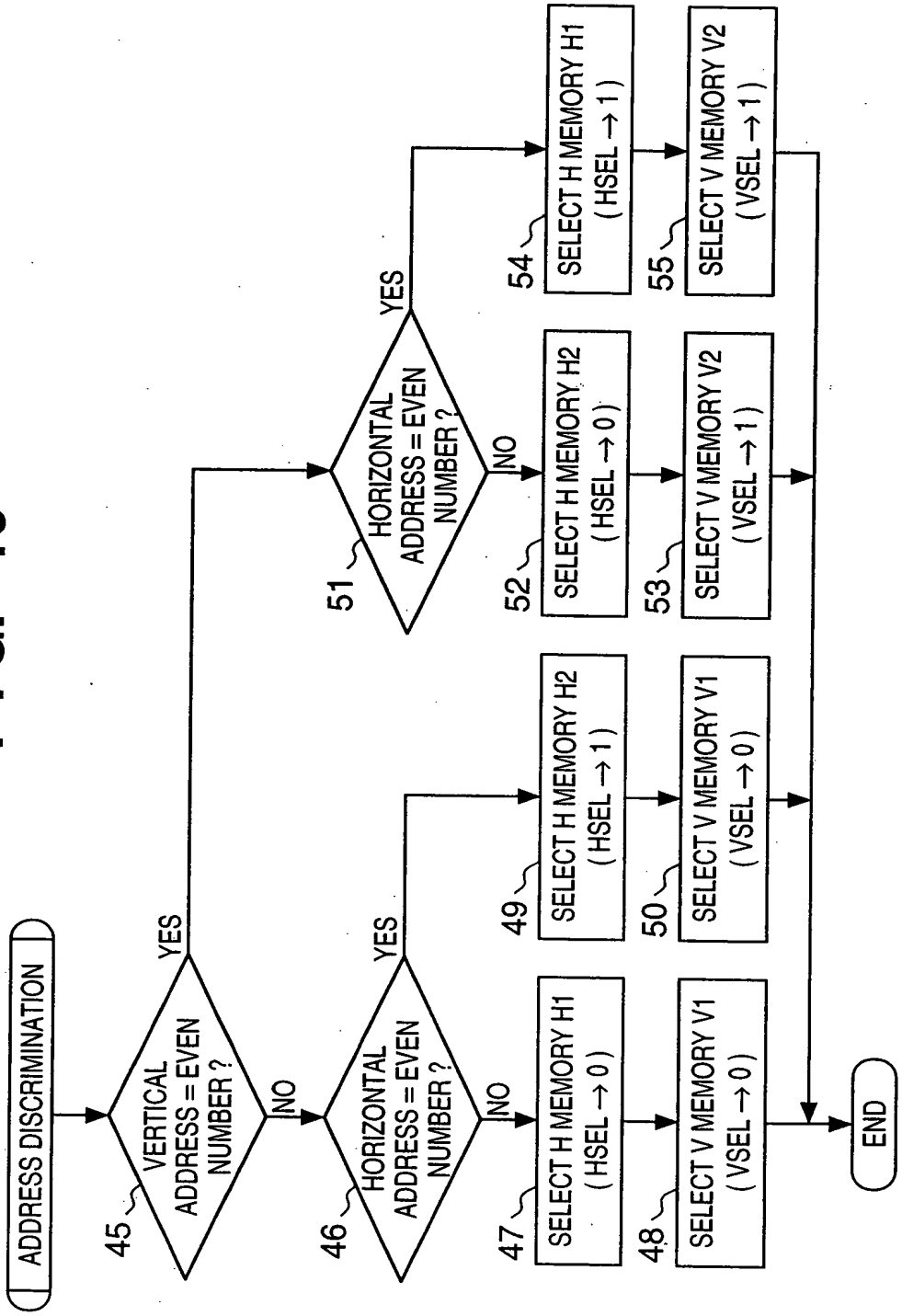

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FIG. 11

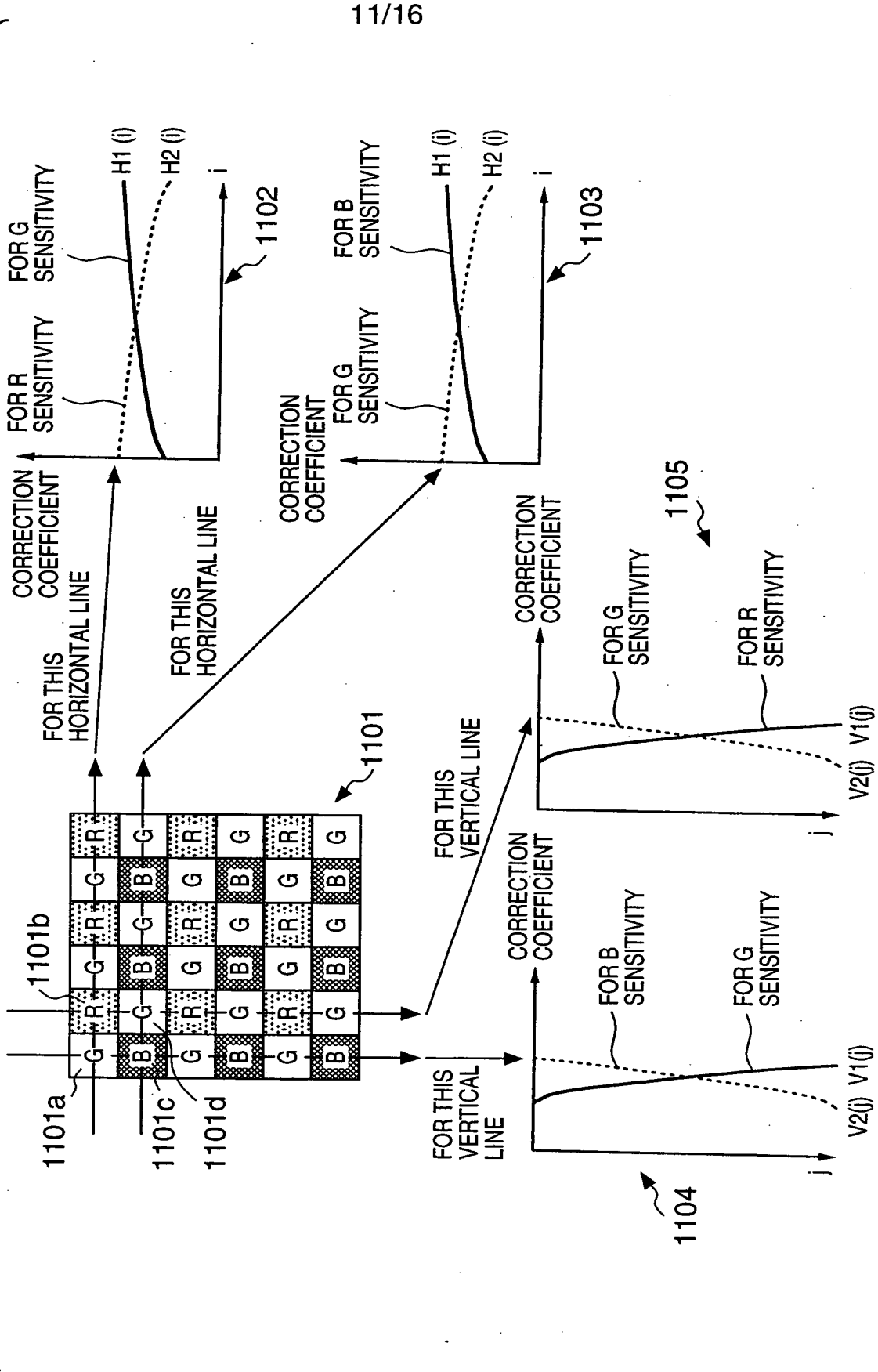

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FIG. 12

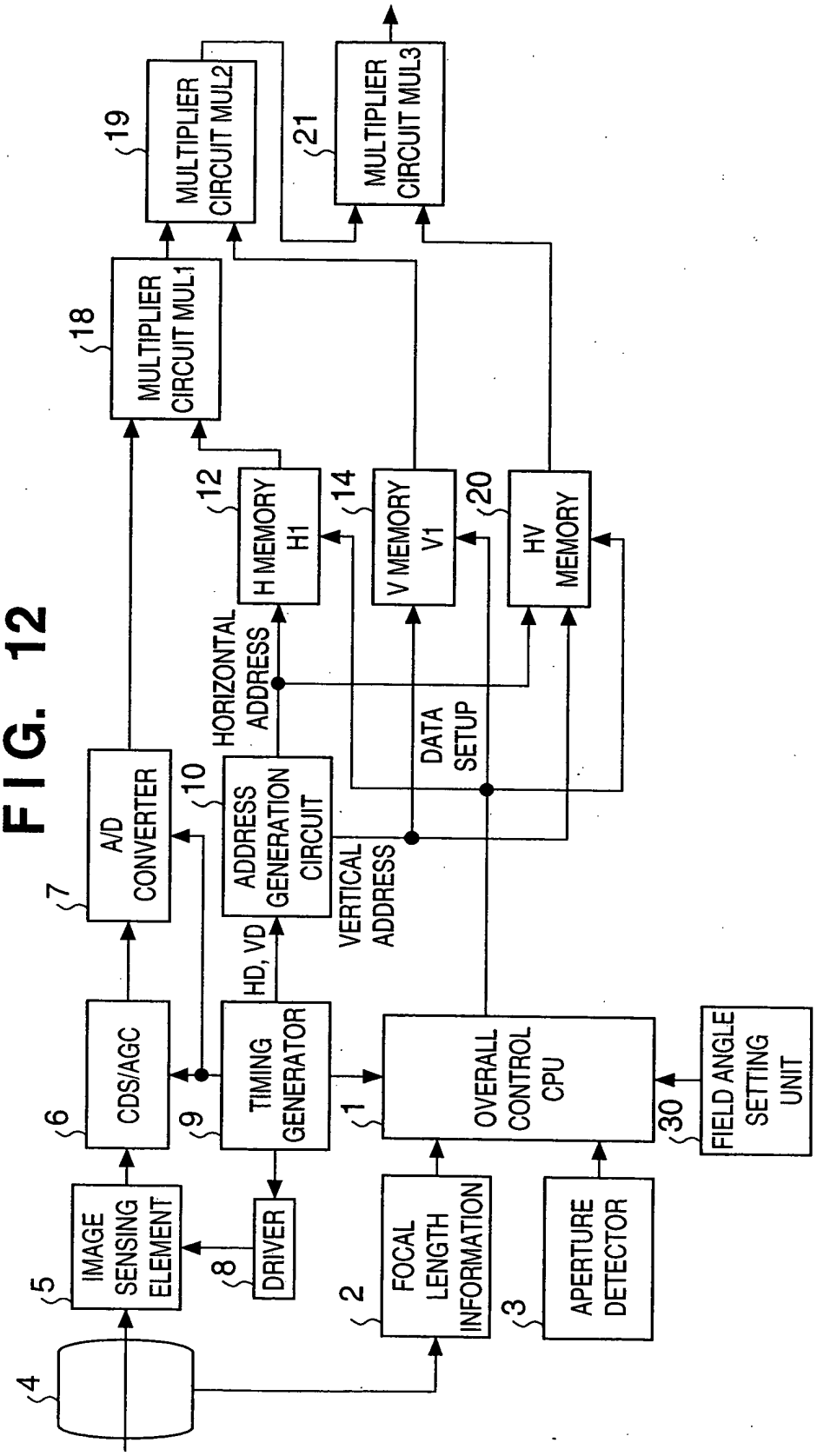

FIG. 13

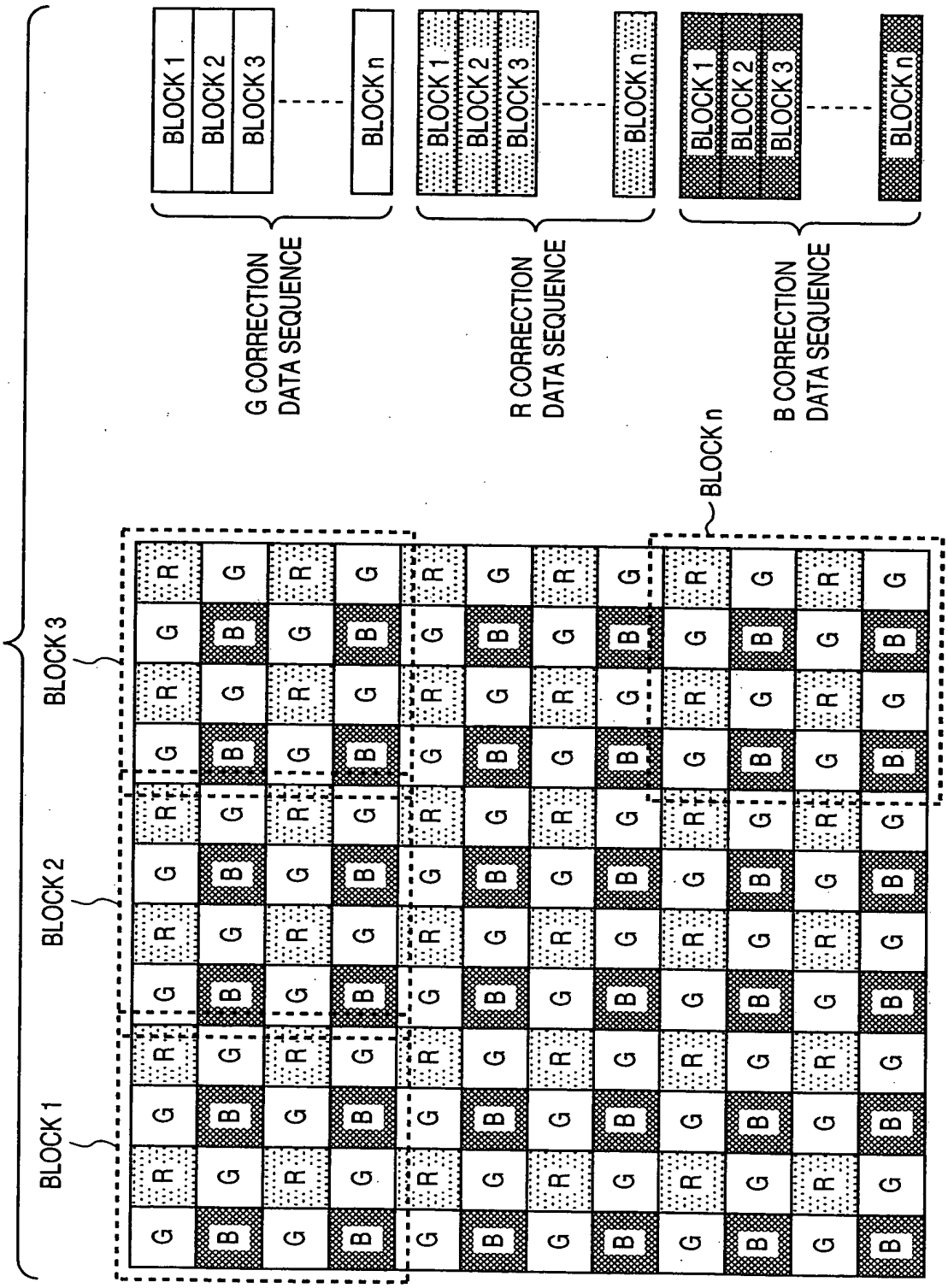
BLOCK 1
BLOCK 2
BLOCK 3
BLOCK n
G CORRECTION DATA SEQUENCE
R CORRECTION DATA SEQUENCE
B CORRECTION DATA SEQUENCE

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FIG. 14

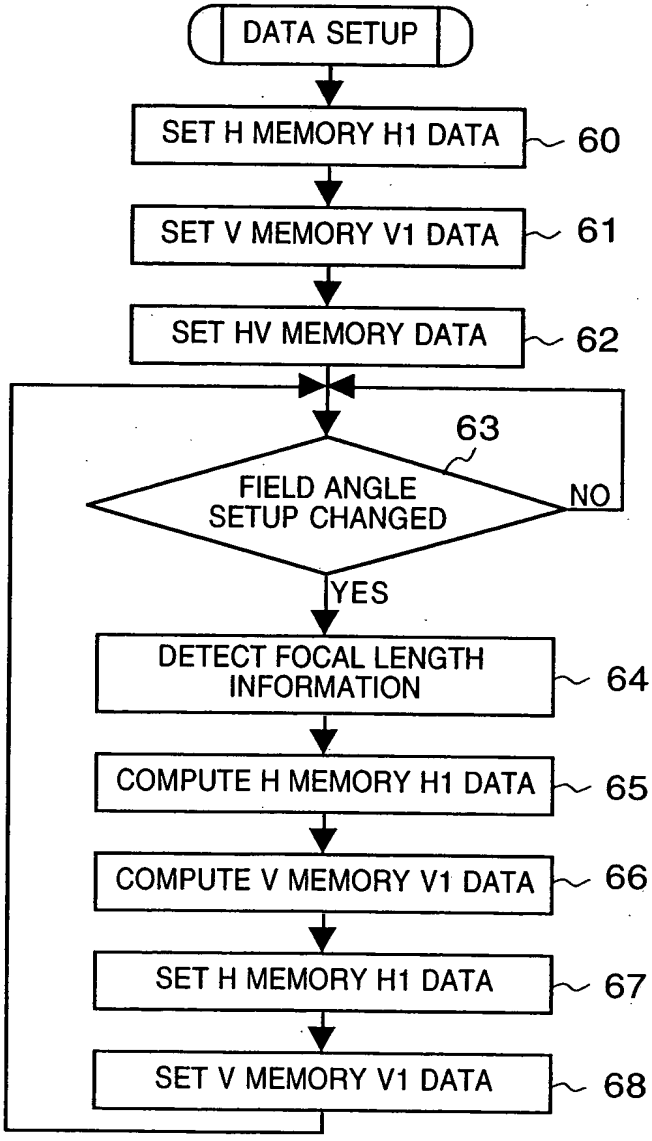

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FIG. 15A

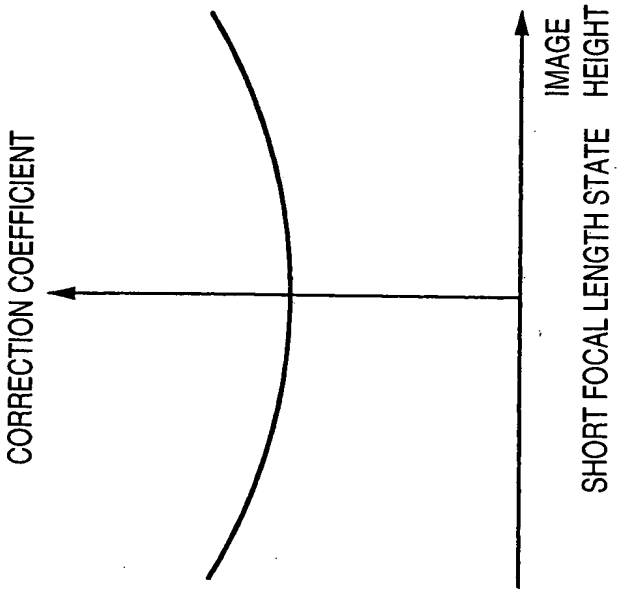
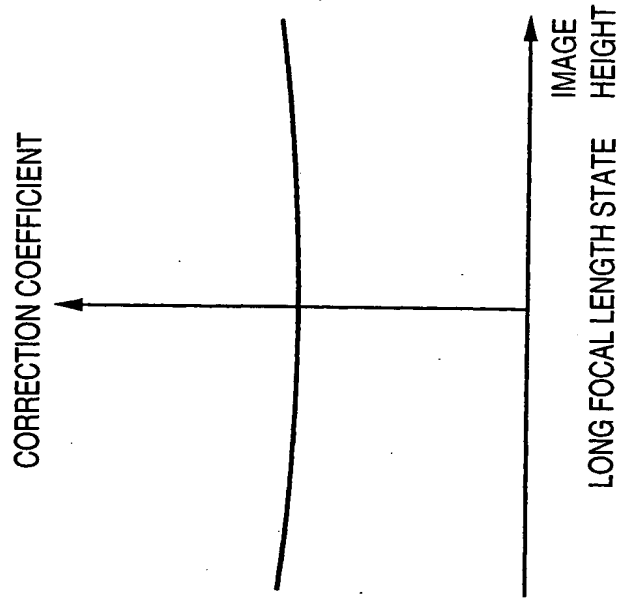


FIG. 15B



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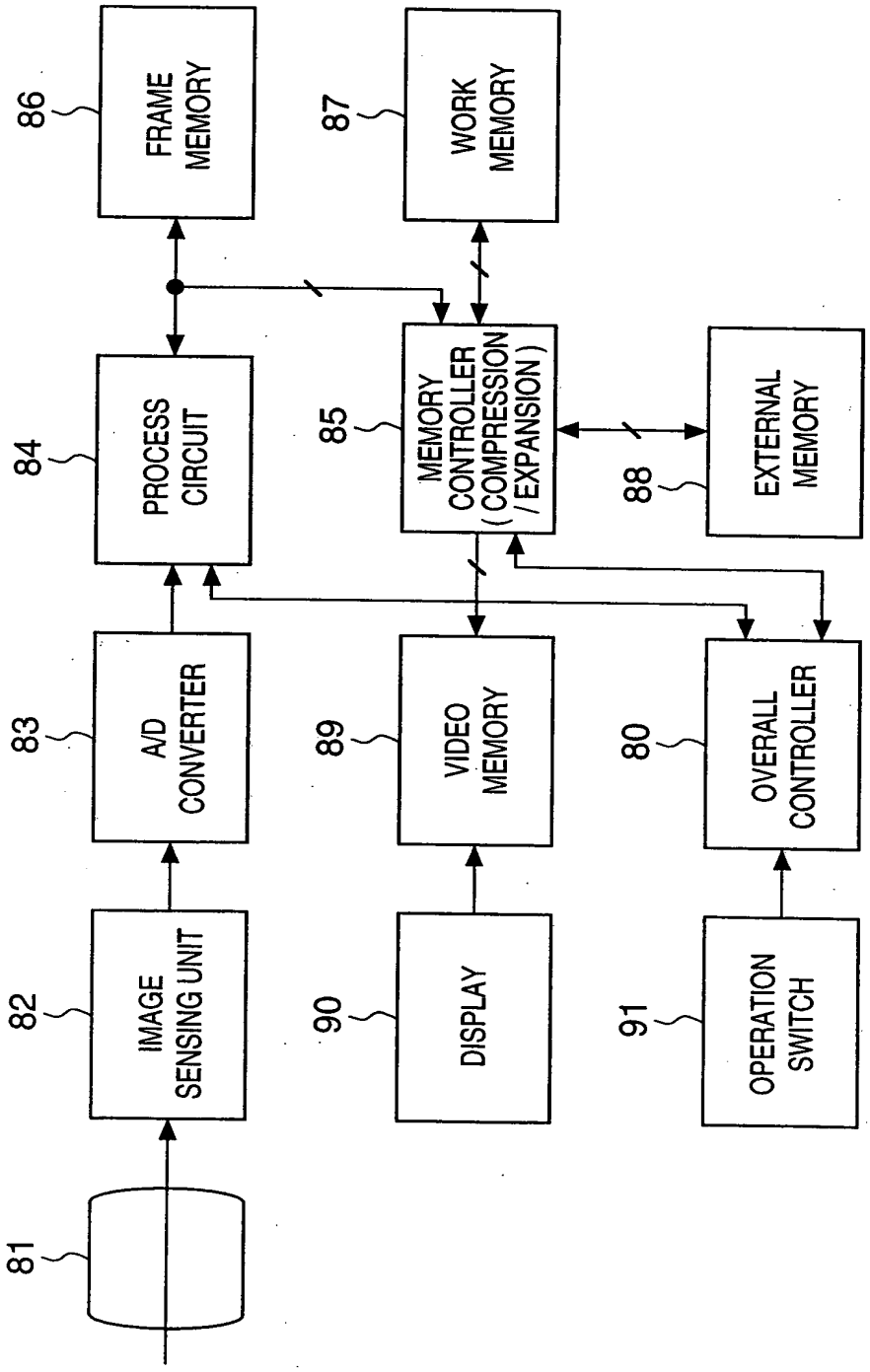
FIG. 16